

FDP030N06 N-Channel PowerTrench[®] MOSFET 60 V, 193 A, 3.2 mΩ

Features

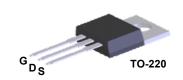
- $R_{DS(on)}$ = 2.6 m Ω (Typ.)@ V_{GS} = 10 V, I_D = 75 A
- · Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low $R_{\text{DS}(\text{on})}$
- High Power and Current Handling Capability
- RoHS Compliant

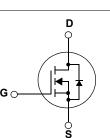
Description

This N-Channel MOSFET is produced using Fairchild Semiconductor[®]'s advanced PowerTrench[®] process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

Applications

- Synchronous Rectification for ATX / Server / Telecom PSU
- Battery Protection Circuit
- Motor Drives and Uninterruptible Power Supplies
- Renewable System





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

| Symbol | Parameter | | | FDP030N06 | Unit |
|-----------------------------------|---|--|--|-------------|------|
| V _{DSS} | Drain to Source Voltage | | 60 | V | |
| V _{GSS} | Gate to Source Voltage | e | | ±20 | V |
| I _D | | -Continuous (T _C = 25 ^o C, S | -Continuous (T _C = 25 ^o C, Silicon Limited) | | A |
| | Drain Current | -Continuous ($T_C = 100^{\circ}C$, | -Continuous (T _C = 100 ^o C, Silicon Limited) | | |
| | | -Continuous (T _C = 25 ^o C, F | ackage Limited) | 120 | |
| I _{DM} | Drain Current | - Pulsed | (Note 1) | 772 | Α |
| E _{AS} | Single Pulsed Avalanche Energy (Note 2) | | (Note 2) | 1434 | mJ |
| dv/dt | Peak Diode Recovery dv/dt (Note 3) | | 6 | V/ns | |
| P _D | Power Dissipation | (T _C = 25 ^o C) | | 231 | W |
| | | - Derate above 25°C | | 1.54 | W/ºC |
| T _J , T _{STG} | Operating and Storage Temperature Range | | | -55 to +175 | °C |
| TL | Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds | | | 300 | °C |

Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 120A.

Thermal Characteristics

| Symbol | Parameter | FDP030N06 | Unit |
|---------------------|---|-----------|-------|
| $R_{	ext{	heta}JC}$ | Thermal Resistance, Junction to Case, Max. | 0.65 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient, Max. | 62.5 | °C/vv |

April 2013

| FDP030N06 Cteristics T _C = 25°C u Parameter cource Breakdown Voltage m Voltage Temperature t e Voltage Drain Current ody Leakage Current eshold Voltage in to Source On Resistance Transconductance | $I_{D} = 2$ $I_{D} = 1$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$ | - ise noted Test Conditions 250 μ A, V _{GS} = 0V, T _C = mA, Referenced to 25' = 48V, V _{GS} = 0V = 48V, T _C = 150°C = ±20V, V _{DS} = 0V = V _{DS} , I _D = 250 μ A = 10V, I _D = 75A | | - Min. 60 | - 0.05 - - - - | 50 Max. - - 1 500 | Unit V V/°C μA | |
|--|--|---|--|---|---|--|--|--|
| Parameter Cource Breakdown Voltage In Voltage Temperature t Voltage Drain Current Ody Leakage Current eshold Voltage in to Source On Resistance Fransconductance | $I_{D} = 2$ $I_{D} = 1$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$ | Test Conditions $250\mu A, V_{GS} = 0V, T_{C} = 0$ mA, Referenced to 25 ^G $48V, V_{GS} = 0V$ $48V, T_{C} = 150^{\circ}C$ $248V, V_{DS} = 0V$ $248V, V_{DS} = 0V$ $48V, V_{DS} = 0V$ | | 60 - - | - 0.05 - - | - - 1 | V V/ºC | |
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| in to Source On Resistance ransconductance | V _{GS} = | | | 2.5 | 3.5 | 4.5 | V | |
| | | - 10V, ID - 73A | | - | 2.6 | 3.2 | mΩ | |
| istics | v _{DS} - | = 10V, I _D = 75A | | - | 154 | - | S | |
| | | | | | | | | |
| acitance | | | | - | 7380 | 9815 | pF | |
| pacitance | | — V _{DS} = 25V, V _{GS} = 0V | | - | 1095 | 1455 | pF | |
| • | f = 1N | ИНz | | - | | | pF | |
| | | | | - | | | nC | |
| - | V _{DS} = 48V, I _D = 75A | | _ | - | 40 | - | nC | |
| | V _{GS} = | V _{GS} = 10V | | - | 35 | - | nC | |
| | | | (NOLE 4) | | | | L | |
| | | | | | 20 | 07 | | |
| , | Vpp = | = 30V lp = 75A | _ | - | | - | ns | |
| | | | _ | - | | | ns ns | |
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| | | | (11018 4) | - | 55 | 10 | 113 | |
| | | | | | | 1 | | |
| | | | | - | - | | A | |
| Im Pulsed Drain to Source Diode Forward Current | | | - | - | | A | | |
| | | | | - | - | | V | |
| | | | _ | | | | ns | |
| ecovery Charge | uiF/ui | - 100Α/μ5 | | - | 50 | - | nC | |
| | Transfer Capacitance a Charge at 10V ource Gate Charge rain "Miller" Charge Pristics Delay Time Fall Time Continuous Drain to Source Pulsed Drain to Source Dio ource Diode Forward Voltag Recovery Time Recovery Charge mited by maximum junction temperat $50V, R_G = 25\Omega, Starting T_J = 25^{\circ}C$ $\leq BV_{DSN}, Starting T_J = 25^{\circ}C$ | Transfer Capacitance T = 1N Transfer Capacitance T = 1N a Charge at 10V VDS = ource Gate Charge VDS = rain "Miller" Charge VGS = pristics VDD = Delay Time VGS = Fall Time VGS = Continuous Drain to Source Diode Forward Cource Diode Forward Voltage VGS = Pulsed Drain to Source Diode Forward Cource Diode Forward Voltage VGS = Recovery Time VGS = Recovery Charge dIF/dt mited by maximum junction temperature intege SQ, Starting TJ = 25°C | T = TMHZ Transfer Capacitance a Charge at 10V ource Gate Charge rain "Miller" Charge VDS = 48V, ID = 75A VGS = 10V eristics Delay Time Notes and the second secon | Transfer Capacitance T = TMHZ a Charge at 10V $V_{DS} = 48V$, $I_D = 75A$ ource Gate Charge $V_{DS} = 48V$, $I_D = 75A$ rain "Miller" Charge $V_{GS} = 10V$ eristics $V_{DD} = 30V$, $I_D = 75A$ Delay Time $V_{SS} = 10V$, $R_{GEN} = 4.7\Omega$ Fall Time $V_{OS} = 10V$, $R_{GEN} = 4.7\Omega$ Fall Time $V_{OS} = 0V$, $I_{SD} = 75A$ Oclay Time $V_{GS} = 0V$, $I_{SD} = 75A$ Continuous Drain to Source Diode Forward Current Pulsed Drain to Source Diode Forward Current Pulsed Drain to Source Diode Forward Current $V_{GS} = 0V$, $I_{SD} = 75A$ Recovery Time $V_{GS} = 0V$, $I_{SD} = 75A$ Recovery Charge $dI_F/dt = 100A/\mu s$ mited by maximum junction temperature $0V, R_G = 25\Omega$, Starting $T_J = 25^{\circ}C$ $\leq V_{DSS}$, Starting $T_J = 25^{\circ}C$ $\leq V_{DSS}$, Starting $T_J = 25^{\circ}C$ | Transfer CapacitanceT = TMHZ-a Charge at 10V $V_{DS} = 48V$, $I_D = 75A$ -ource Gate Charge $V_{DS} = 48V$, $I_D = 75A$ -rain "Miller" Charge $V_{GS} = 10V$ (Note 4)cristicsDelay Time $V_{DD} = 30V$, $I_D = 75A$ -Delay Time $V_{CS} = 10V$, $R_{GEN} = 4.7\Omega$ -Fall Time $V_{OS} = 10V$, $R_{GEN} = 4.7\Omega$ -Continuous Drain to Source Diode Forward Current-Pulsed Drain to Source Diode Forward Current-Pulsed Drain to Source Diode Forward Current-ource Diode Forward Voltage $V_{GS} = 0V$, $I_{SD} = 75A$ -Recovery Time $V_{GS} = 0V$, $I_{SD} = 75A$ -Recovery Charge $dI_F/dt = 100A/\mu s$ -mited by maximum junction temperature $0V, R_G = 25\Omega$, Starting $T_J = 25^{\circ}C$ - SV_{DSS} , Starting $T_J = 25^{\circ}C$ - | Transfer CapacitanceT = TMHZ-415iource Gate ChargeVDS = 48V, ID = 75A-116ource Gate ChargeVDS = 48V, ID = 75A-40rain "Miller" ChargeVDS = 10V-35eristicsDelay Time-39Rise Time-39Oblay Time-39Collay Time-39Oblay Time-39Oblay Time-39Colspan="4">Oblay Time-39Oblay Time-178Oblay Time-54Colspan="4">Oblay Time-54Colspan="4">Oblay Time-54Oblay Time54Colspan="4">Oblay TimeOblay TimeOblay TimeVGS = 0V, ISD = 75AOblay TimeVGS = 0V, ISD = 75AOblay Colspan= 75AOblay TimeVGS = 0V, ISD = 75AOblay Colspan= 75AOblay Colspan= 75AOblay Colspan= 75AOblay Colspan= 75AOblay Colspan= 75AOblay Colspan= 75A <td colspa<="" td=""><td>Transfer Capacitance T = TIMHZ - 415 625 a Charge at 10V $V_{DS} = 48V, I_D = 75A$ - 116 151 ource Gate Charge $V_{GS} = 10V$ - 40 - rain "Miller" Charge $V_{GS} = 10V$ - 35 - pristics - 178 366 - 178 366 Delay Time V_{DD} = 30V, I_D = 75A - 178 366 - 54 118 call Time V_{GS} = 10V, R_{GEN} = 4.7\Omega - 54 118 - 54 118 call Time V_{OS} = 0V, I_S = 75A - 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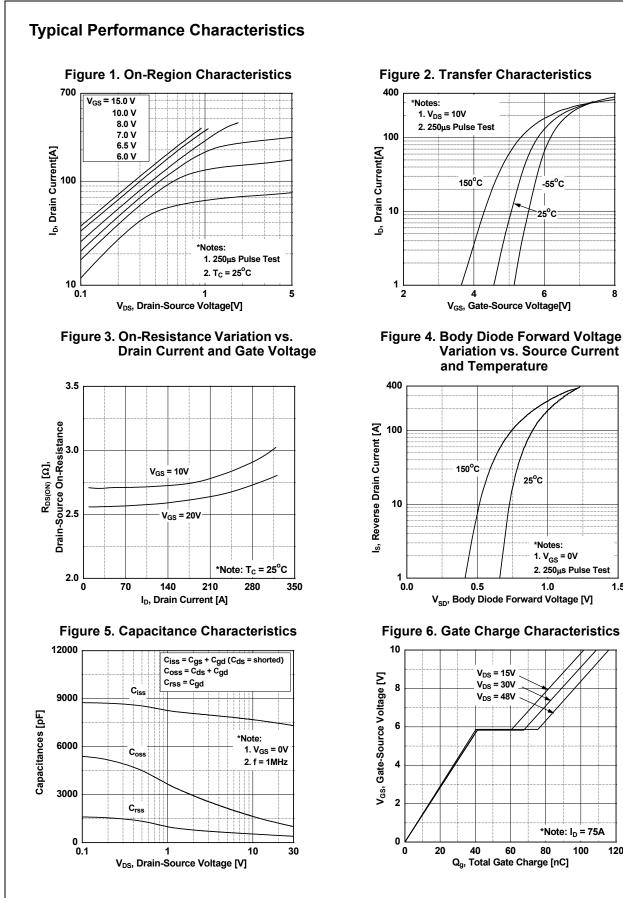


Figure 2. Transfer Characteristics

-55°C

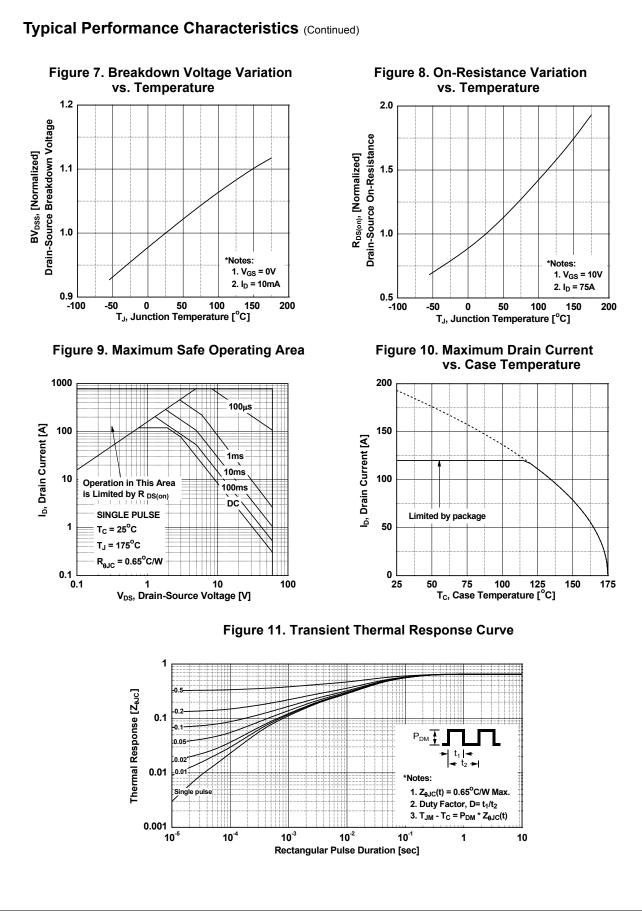
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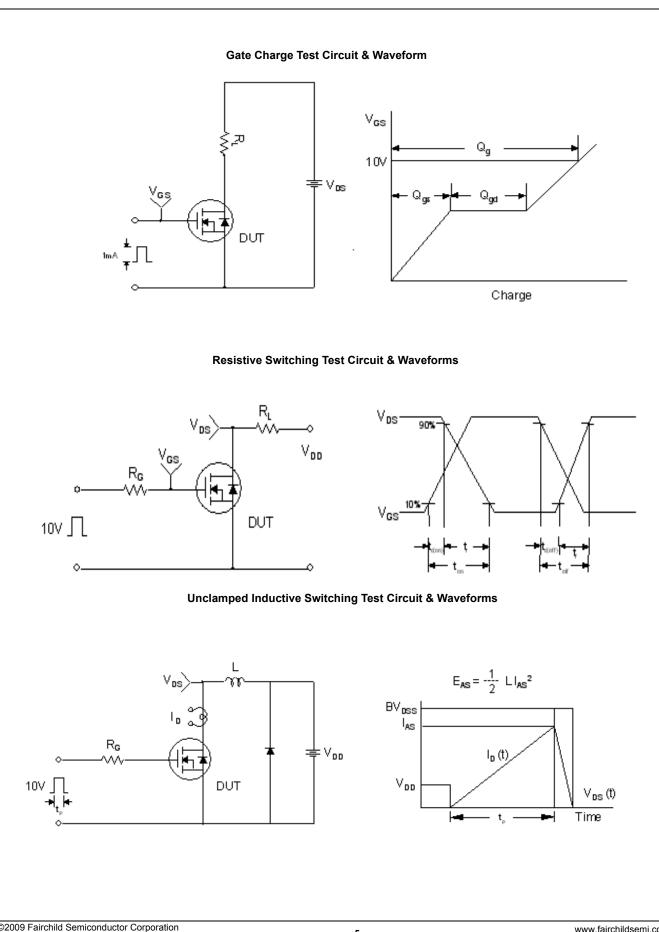
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1.5

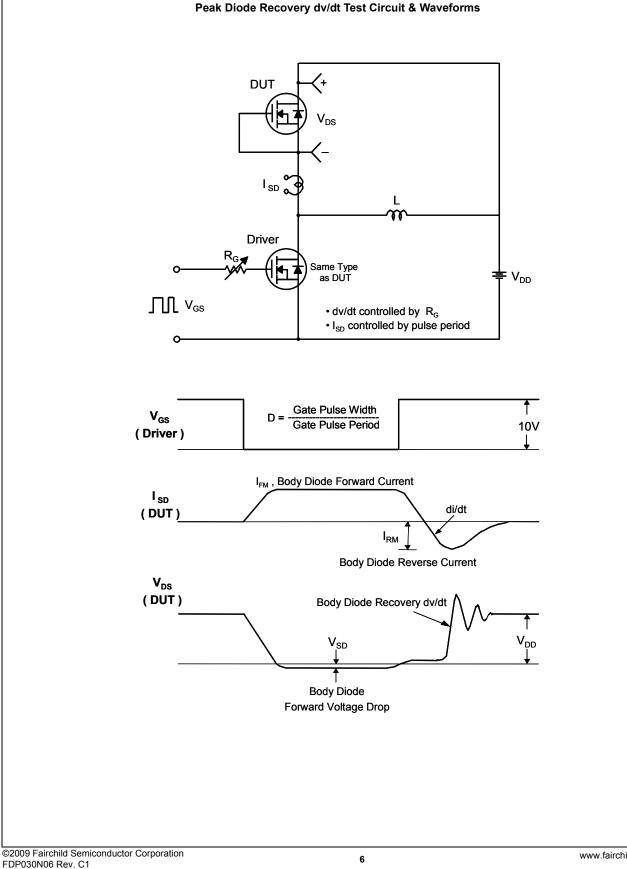
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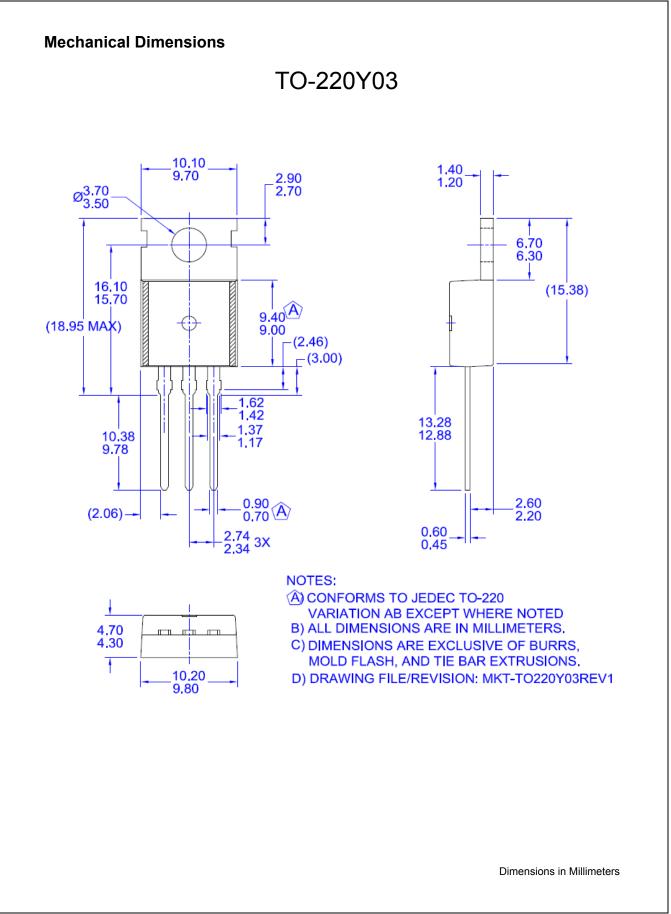
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| • | | Rev. I |